

BEST AVAILABLE COPY**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application Serial No. 10/659,596
Confirmation No. 5277
Filing Date September 9, 2004
Inventor Fernando Gonzalez
Assignee Micron Technology, Inc.
Group Art Unit 2818
Examiner Thao P. Le
Attorney's Docket No. MI22-2393
Customer No. 021567
Title: Methods Of Forming Semiconductor Constructions

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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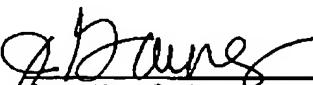
CERTIFICATE OF FACSIMILE TRANSMISSION UNDER 37 CFR § 1.8

I hereby certify that the following papers are being facsimile transmitted to the Patent and Trademark Office at (703) 872-9306 on the date shown below:

1. Certificate of Facsimile Transmission
2. Request to have a Previously-Filed Information Disclosure Statement Considered
3. Previously filed IDS w/PTO form 1449, filed on 9/9/2003 (Examiner to please initial and fax back)

Dated: February 16, 2005

By:



Jennifer Gaines, Legal Assistant
Telephone No. (509) 624-4276
Facsimile No. (509) 838-3424

FEE DEFICIENCY

Although it is believed that no fees are due, the Commissioner is hereby authorized to charge any fees under 37 C.F.R. 1.16 and 1.17 which may be required by this paper to Deposit Account No. 23-0925.

Dated: February 16, 2005

By:


David G. Latwesen, Ph.D.
Reg. No. 38,533

NUMBER OF PAGES IN FACSIMILE: 6

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From: David G. Latwesen, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

**REQUEST TO HAVE A PREVIOUSLY-FILED INFORMATION DISCLOSURE
STATEMENT CONSIDERED**

Applicant submitted an Information Disclosure Statement and accompanying Form PTO-1449 on September 9, 2003 pertaining to the present application (a courtesy copy of the Information Disclosure Statement and Form PTO-1449 is provided herewith), and received a Notice of Allowance which was mailed January 11, 2005. Since the filing date of the Information Disclosure Statement predates the mailing of the Notice of Allowance, Applicant respectfully requests that the subject matter cited to the

Patent Office on the Form PTO-1449 accompanying the Information Disclosure Statement be considered by the Patent Office, and that an Examiner-initialed copy of the Form PTO-1449 be returned to the undersigned in the event that the Examiner finds the claims of the present application to be allowable over the subject matter disclosed on the Form PTO-1449. Applicant notes that the Examiner already consider the first page of the Information Disclosure Statement, as evidenced by the Examiner's including an initialed copy of the first page with an Office Action mailed August 9, 2004, but the Examiner has not returned any evidence to show that the second page of the Information Disclosure Statement was considered.

The undersigned respectfully requests that the Examiner call the undersigned when considering this request so that the undersigned may know if the signed second page of the Information Disclosure Statement will be coming prior to the April 11, 2005 deadline for paying the issue fee for the present application.

Respectfully submitted,

Dated: February 16, 2005

By:


David G. Latwesen, Ph.D.
Reg. No. 38,533

5
EV3182833495
Inventor: **Fernando Gonzalez**
Title: **Methods of Forming Semiconductor Constructions**
Assignee: **Micron Technology, Inc.**
PRIORITY Serial No.: **09/592,604**
PRIORITY Filing Date: **June 12, 2000**

COPY

INFORMATION DISCLOSURE STATEMENT

PURSUANT TO 37 C.F.R. §§1.56, 1.97 AND 1.98

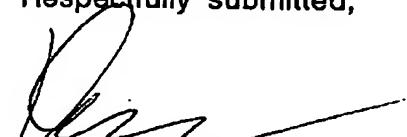
In compliance with 37 C.F.R. §§1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a continuation of co-pending application Serial No. 09/592,604 filed June 12, 2000. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: September 9, 2003 Attorney:



David G. Latwesen, Ph.D.
Reg. No. 38,533
Wells, St. John P.S.

Sheet 1 of 2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2393	PRIORITY SERIAL NO. 09/592,604		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Fernando Gonzalez			
				PRIORITY FILING DATE June 12, 2000	PRIORITY GROUP 2818		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,298,449	03/94	Kikuchi			
	AB	5,374,564	12/94	Bruehl			
	AC	5,835,693	01/99	Murari et al.			
	AD	5,877,070	03/99	Ooscale et al.			
	AE	5,882,967	03/99	Srikrishnan			
	AF	5,894,152	04/99	Jaso et al.			
	AG	5,953,622	09/99	Lee et al.			
	AH	6,004,406	12/99	Kobayashi et al.			
	AI	6,309,945 B1	10/01	Sato et al.			
	AJ	6,429,070 B1	08/02	Gonzalez et al.			
	AK	6,384,439 B1	05/02	Walker			
		6,423,992 B2	07/02	Fukuda, et al.			
	AL	5,998,847	12/99	Azadereghi, et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AM						No
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR	Ooscale, U. et al., "Semiconductor Wafer Bonding: Science, Technology, and Applications", Electrochemical Society Proceedings					
		Vol. 97-36, (©1998), pp. 400-415, 436-445.					
	AS						
EXAMINER			DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Sheet 2 of 2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2393	PRIORITY SERIAL NO. 09/592,604		
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				PRIORITY FILING DATE June 12, 2000	PRIORITY GROUP 2818		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,251,754	6/01	Kobayashi et al.			
	AB	6,245,161	6/01	Henley et al.			
	AC	5,374,581	12/94	Ichikawa et al.			
	AD	4,891,329	1/90	Reisman et al.			
	AE	6,150,031	11/00	Yonehara			
	AP	6,083,324	7/00	Henley et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
							No
	AN						
	AO						
	AP						
	AQ						
	AR						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AS						
	AT						
EXAMINER			DATE CONSIDERED				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

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